DOCUMENT CHANGE REQUEST

DCR number	1027	Changes required for: General	Originator: Jean-Paul Bussenot
Date: 2022/11/10		Date sent: 2016/08/24	Organisation: CNES
Status: IMPLEMENTED			

Title:	Generic Specification for Capacitors Fixed Chips Ceramic Dielectric Types I and II		
Number:	3009	Issue:	4

Other documents affected:

3502-4, 4008-4, 5000-10

Page:

28

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

ESCC

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General	Originator: Jean-Paul Bussenot
Date: 2022/11/10	Date sent: 2016/08/24	Organisation: CNES
Status: IMPLEMENTED		

Title:	Generic Specification for Ferrite Microwave Components Isolators and Circulators		
Number:	3202	Issue:	3

Other documents affected:

Page:

40

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General	Originator: Jean-Paul Bussenot	
Date: 2022/11/10	Date sent: 2016/08/24	Organisation: CNES	
Status: IMPLEMENTED			

Title:	Generic Specification for Attenuators and Loads RF Coaxial Fixed		
Number:	3403	Issue:	7

Other documents affected:

4001-5

Page:

33

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027

Changes required for: General

Originator: Jean-Paul Bussenot

Date: 2022/11/10

Date sent: 2016/08/24

Organisation: CNES

Status: IMPLEMENTED

Title:	Generic Specification for CRYSTAL CONTROLLED OSCILLATORS		
Number:	3503	Issue:	5

Other documents affected:

Page:

38

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General		Originator: Jean-Paul Bussenot
Date: 2022/11/10	Date sent: 2016/08/24		Organisation: CNES
Status: IMPLEMENTED			
Title:	Generic Specification for Relays Electromagnetic Non-Latching		
Number:	3601	Issue:	5

Other documents affected:

3602-5

Page:

37

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General	Originator: Jean-Paul Bussenot
Date: 2022/11/10	Date sent: 2016/08/24	Organisation: CNES
Status: IMPLEMENTED		

Title:	Generic Specification for Thermistors (Resistors Thermally Sensitive)		
Number:	4006	Issue:	4

Other documents affected:

Page:

34

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General	Originator: Jean-Paul Bussenot
Date: 2022/11/10	Date sent: 2016/08/24	Organisation: CNES
Status: IMPLEMENTED		

Title:	Generic Specification for Resistors Heaters Flexible		
Number:	4009	Issue:	7

Other documents affected:

Page:

27

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027	Changes required for: General	Originator: Jean-Paul Bussenot
Date: 2022/11/10	Date sent: 2016/08/24	Organisation: CNES
Status: IMPLEMENTED		

Title:	Generic Specification for Discrete Microwave Semiconductor Components		
Number:	5010	Issue:	3

Other documents affected:

Page:

35

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

DOCUMENT CHANGE REQUEST

DCR number 1027

Changes required for: General

Originator: Jean-Paul Bussenot

Date: 2022/11/10

Date sent: 2016/08/24

Organisation: CNES

Status: IMPLEMENTED

Title:	Integrated Circuits: Monolithic And Multichip Microcircuits,Wire-Bonded, Hermetically Sealed And		
Number:	9000	Issue:	11

Other documents affected:

Page:

36

Paragraph:

12.4

Original wording:

CHART F4 – QUALIFICATION AND PERIODIC TESTS

Proposed wording:

CHART F4 – QUALIFICATION, PERIODIC TESTS AND LOT VALIDATION TESTING

Justification:

Clarification - Manufacturers claim that many users do not understand that Lot validation Testing refers to Chart F4

Attachments:

N/A

Modifications:

improve clarity in chart F4

Approval signature:

Date signed:

2022-11-10